

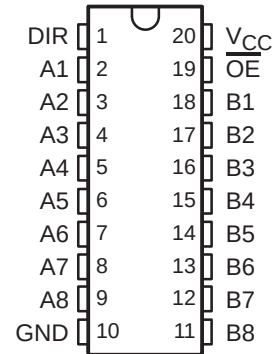
CD74FCT245

BiCMOS OCTAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCBS721 – JULY 2000

- BiCMOS Technology With Low Quiescent Power
- Buffered Inputs
- Noninverted Outputs
- Input/Output Isolation From V_{CC}
- Controlled Output Edge Rates
- 64-mA Output Sink Current
- Output Voltage Swing Limited to 3.7 V
- SCR Latch-Up-Resistant BiCMOS Process and Circuit Design
- Package Options Include Plastic Small-Outline (M) and Shrink Small-Outline (SM) Packages and Standard Plastic (E) DIP

E, M, OR SM PACKAGE
(TOP VIEW)



description

The CD74FCT245 is an octal bus transceiver with 3-state outputs using a small-geometry BiCMOS technology. The output stages are a combination of bipolar and CMOS transistors that limit the output high level to two diode drops below V_{CC} . This resultant lowering of output swing (0 V to 3.7 V) reduces the power-bus ringing [a source of electromagnetic interference (EMI)] and minimizes V_{CC} bounce and ground bounce and their effects during simultaneous output switching. The output configuration also enhances switching speed and is capable of sinking 64 mA.

The CD74FCT245 allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending upon the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so that the buses are effectively isolated.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The CD74FCT245 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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The logic diagram of the 74147 decoder shows the internal circuitry. It includes two 3-input AND gates at the top, two 2-input AND gates in the middle, and two inverters at the bottom. The inputs are DIR (1), A1 (2), and B1 (18). The output of the top-left 3-input AND gate is connected to pin 19 (OE). The output of the top-right 3-input AND gate is connected to pin 18 (B1). The output of the middle-left 2-input AND gate is connected to pin 19 (OE). The output of the middle-right 2-input AND gate is connected to pin 18 (B1). The output of the bottom-left inverter is connected to pin 19 (OE). The output of the bottom-right inverter is connected to pin 18 (B1). The outputs of the two 2-input AND gates are connected to a common bus labeled "To Seven Other Channels".

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

DC supply voltage range, V_{CC}	–0.5 V to 6 V
DC input clamp current, I_{IK} ($V_I < -0.5$ V)	–20 mA
DC output clamp current, I_{OK} ($V_O < -0.5$ V)	–50 mA
DC output sink current per output pin, I_{OL}	70 mA
DC output source current per output pin, I_{OH}	–30 mA
Continuous current through V_{CC} , I_{CC}	140 mA
Continuous current through GND)	528 mA
Package thermal impedance, θ_{JA} (see Note 1): E package)	69°C/W
M package)	58°C/W
SM package)	70°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 2)

	MIN	MAX	UNIT
V_{CC} Supply voltage	4.75	5.25	V
V_{IH} High-level input voltage	2		V
V_{IL} Low-level input voltage		0.8	V
V_I Input voltage	0	V_{CC}	V
V_O Output voltage	0	V_{CC}	V
I_{OH} High-level output current		–15	mA
I_{OL} Low-level output current		64	mA
$\Delta t/\Delta v$ Input transition rise or fall rate	0	10	ns/V
T_A Operating free-air temperature	0	70	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	$T_A = 25^\circ\text{C}$		MIN	MAX	UNIT
			MIN	MAX			
V_{IK}	$I_I = -18$ mA	4.75 V	–1.2		–1.2		V
V_{OH}	$I_{OH} = -15$ mA	4.75 V	2.4		2.4		V
V_{OL}	$I_{OL} = 64$ mA	4.75 V		0.55		0.55	V
I_I	$V_I = V_{CC}$ or GND	5.25 V		± 0.1		± 1	μA
I_{OZ}	$V_O = V_{CC}$ or GND	5.25 V		± 0.5		± 10	μA
$I_{OS}^\ddagger$	$V_I = V_{CC}$ or GND, $V_O = 0$	5.25 V	–60		–60		mA
I_{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.25 V		8		80	μA
$\Delta I_{CC}^\S$	One input at 3.4 V, Other inputs at V_{CC} or GND	5.25 V		1.6		1.6	mA
C_i	$V_I = V_{CC}$ or GND			10		10	pF
C_o	$V_O = V_{CC}$ or GND			15		15	pF

[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed 100 ms.

[§] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC} .

CD74FCT245

BiCMOS OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating conditions (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$T_A = 25^\circ\text{C}$	MIN	MAX	UNIT
			TYP			
t_{pd}	A or B	B or A	5	1.5	7	ns
t_{en}	$\overline{OE}$	A or B	6	1.5	9.5	ns
t_{dis}	$\overline{OE}$	A or B	6	1.5	7.5	ns

noise characteristics, $V_{CC} = 5\text{ V}$, $C_L = 50\text{ pF}$, $T_A = 25^\circ\text{C}$

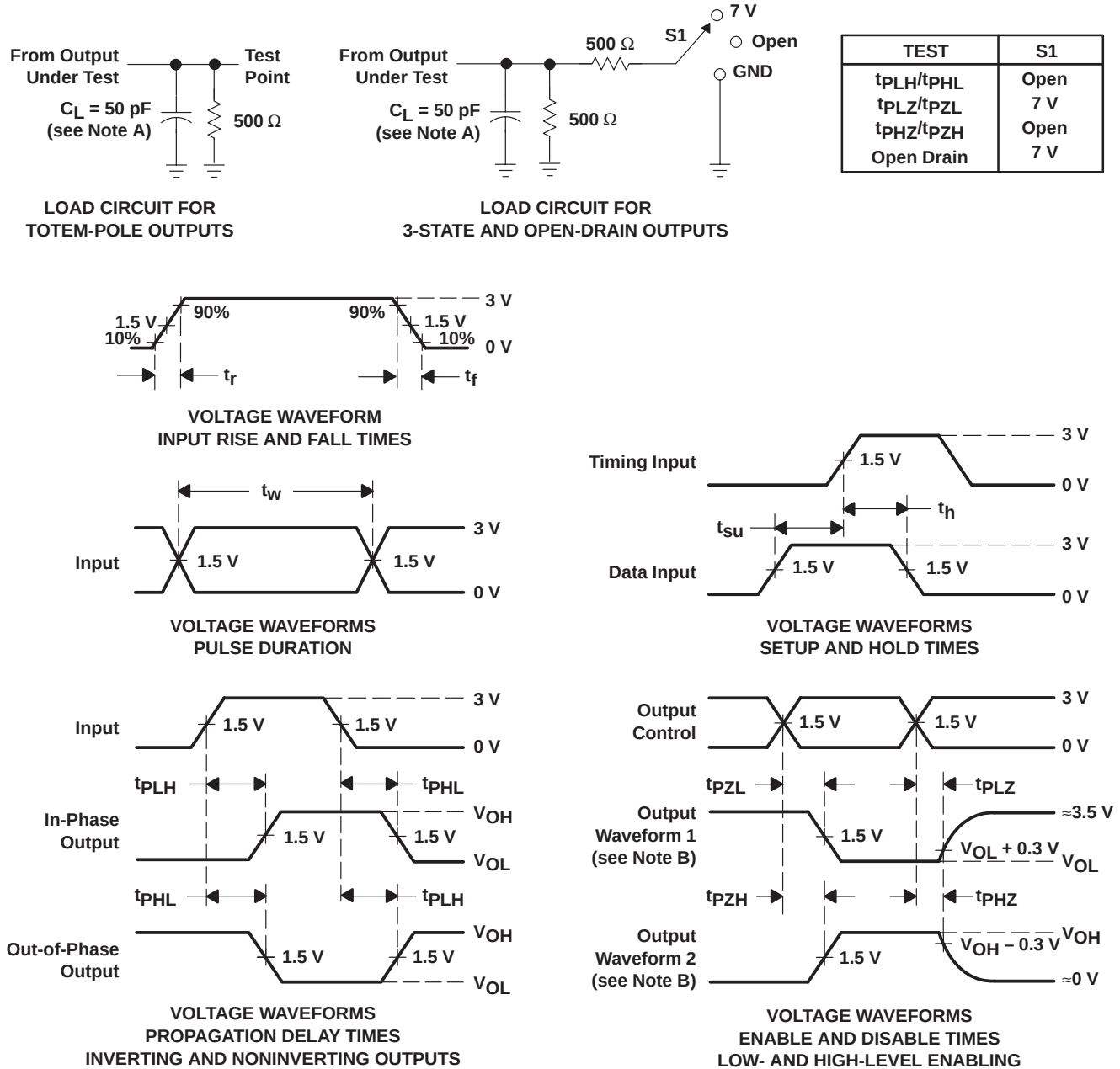
PARAMETER	MIN	TYP	MAX	UNIT
$V_{OL(P)}$ Quiet output, maximum dynamic V_{OL}		1		V
$V_{OH(V)}$ Quiet output, minimum dynamic V_{OH}		0.5		V
$V_{IH(D)}$ High-level dynamic input voltage	2			V
$V_{IL(D)}$ Low-level dynamic input voltage			0.8	V

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	No load, $f = 1\text{ MHz}$	49	pF



PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O = 50 \Omega$, t_r and $t_f = 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PHL} and t_{PLH} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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